

PATENT  
Serial No. 09/787,096  
Amendment in Reply to Final Office Action mailed on January 23, 2006

IN THE SPECIFICATION

Please amend the specification as follows:

Replace the paragraph on page 2, between lines 18-27 of the specification with the following:

The present invention more particularly relates to a method of acquiring the information for specifying the defect locations. Until now it is customary to acquire said information by recording dummy data on the recording disc during a test session and to read out the recorded dummy data and subsequently compare said data with the source data. It is then customary to examine all the blocks of all the recording tracks on the recording disc in this manner. This has been described clearly in, for example, EP-A 0 798 716, ~~from which the preamble of Claim 1 is known.~~ However, such a method has the drawback that it takes much time. This is a drawback particularly in the case of, for example, a video recorder, since a user may expect that a video recorder is ready for recording fairly rapidly after insertion of a new disc.

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Replace the paragraph on page 10, between lines 11-23 of the specification with the following:

If in the step 103 it is found that the track being tested is defective, the sequence number of this track is stored in a list in a step 141, said list being stored in the memory 25 and being referred to as "primary defect list". This is the case, for example, for the second test track 2T2 and the third test track 2T3. Now, in contradistinction to the method described with reference to Figure 3, it is not determined which adjacent tracks are affected: for the time being it is assumed that all the tracks 2 in the area between the examined test track and the test track directly preceding it are "suspect". This is also assumed for all the tracks 2 in the area between the examined test track and the test track directly following it. These two areas together will be referred to as the "suspect area" 3T; ~~Figure 4~~ Figure 1 shows two suspect areas 3T2 and 3T3, which correspond to the test tracks 2T2 and 2T3, respectively. Thus, each suspect area 3T comprises 2N tracks. In a step 142 the suspect area 3T is stored in a list referred to as the "alarm list" in the memory 25.